

Notice of References Cited	Application/Control No. 10/820,421	Applicant(s)/Patent Under Reexamination CHIU ET AL.	
	Examiner John Juba, Jr.	Art Unit 2872	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-6,251,297	06-2001	Komuro et al.	216/24
	C	US-			
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	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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NON-PATENT DOCUMENTS

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	U	Zhaoning Yu, et al., "Novel reflection polarizers with double-layer subwavelength metal grating structure", Conf. on Lasers & Electro-Optics, 1999, CLEO '99 , Summaries of papers presented at conf. on, pp. 420-421 (CThK36), May 1999.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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